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## 2 *Details of Catalyst characterization*

3 The weight percentage of K element in the samples was determined by  
4 inductively coupled plasma-optical emission spectroscopy (ICP-OES, 730, Agilent,  
5 USA).

6 The X-ray diffraction (XRD) experiments were carried out on a Shimadzu 7000S  
7 X-ray diffractometer. The scan rates were  $6^{\circ}\cdot\text{min}^{-1}$  and  $0.5^{\circ}\cdot\text{min}^{-1}$  for the regular scan  
8 and step scan, respectively.

9 Raman spectra were acquired on the Renishaw inVia Raman Microscope. The  
10 laser power was fixed at 2.5 mW produced by an excitation source with a wavelength  
11 of 532 nm. About 0.05 g of catalyst powder was pressed into thin wafer and then  
12 mounted onto the sample holder for observation.

13 Fourier-transform infrared (FT-IR) spectra of the samples were collected on an  
14 FT-IR spectrometer (Nicolet 870, Thermo, USA) by potassium bromide pellet method.  
15 The spectra were obtained at a resolution of  $4\text{ cm}^{-1}$  averaged over 32 scans.

16 The specific surface area ( $S_{\text{BET}}$ ) of the catalysts was measured using the  $\text{N}_2$   
17 adsorption BET method at  $-196\text{ }^{\circ}\text{C}$  (Autosorb-iQ-C, Quantachrome, USA). The  
18 sample was first degassed at  $100\text{ }^{\circ}\text{C}$  for 4 h before measurement.

19 The particle morphology was observed by scanning electron microscopy (SEM,  
20 Nova NanoSEM 450, FEI, USA) and transmission electron microscopy (TEM, Tecnai  
21 G<sup>2</sup> F20, FEI, USA). The lattice images were taken using high-resolution TEM  
22 (HRTEM). The distributions of Mn, O, K, Ce and Cu elements on the surface of the  
23 catalysts were provided by the energy dispersive X-ray spectrometry (EDS) mapping

1 images.

2 The X-ray photoelectron spectroscopy (XPS) was used to analyze the chemical  
3 states of surface elements on an X-ray photoelectron spectrometer (ESCALAB 250Xi,  
4 Thermo Fisher, USA). The XPS spectra were calibrated by referencing the C 1s signal  
5 at 284.6 eV.

6 Temperature programmed reduction by hydrogen ( $H_2$ -TPR) was carried out on  
7 Chemisorption Analyzer (Autochem II 2920, Micromeritics, USA). First,  $\sim 0.05$  g of  
8 catalyst was pretreated in  $50 \text{ mL}\cdot\text{min}^{-1}$  of helium stream at  $100 \text{ }^\circ\text{C}$  for 30 min, and  
9 cooled down to room temperature in the same atmosphere afterwards. Then the  
10 catalyst was purged by  $50 \text{ mL}\cdot\text{min}^{-1}$  of 5 vol.%  $H_2$ /Ar until the baseline of the thermal  
11 conductivity detector (TCD) became stable. The temperature was linearly increased to  
12  $700 \text{ }^\circ\text{C}$  with a heating rate of  $5 \text{ }^\circ\text{C}\cdot\text{min}^{-1}$  for reduction. An isopropyl alcohol / liquid  
13 nitrogen slurry, which was placed upstream of the TCD, was used as cold trap ( $-80 \text{ }^\circ\text{C}$ )  
14 to condense any formed water before the outlet gas entered the detector.

15 Temperature programmed desorption of  $O_2$  ( $O_2$ -TPD) was also performed on the  
16 Chemisorption Analyzer with  $\sim 0.05$  g of catalyst. After pretreated in the same  
17 conditions as those of  $H_2$ -TPR, the catalyst was switched to  $50 \text{ mL}\cdot\text{min}^{-1}$  of 5 vol.%  
18  $O_2$ /He for 0.5 h, which was followed by purging with  $50 \text{ mL}\cdot\text{min}^{-1}$  of helium for 0.5 h  
19 to remove the physisorbed  $O_2$ . The  $O_2$  desorption was carried out in  $50 \text{ mL}\cdot\text{min}^{-1}$  of  
20 helium from room temperature to  $850 \text{ }^\circ\text{C}$  with a heating rate of  $5 \text{ }^\circ\text{C}\cdot\text{min}^{-1}$ . The cold  
21 trap of isopropyl alcohol / liquid nitrogen slurry was also used during  $O_2$  desorption  
22 stage.